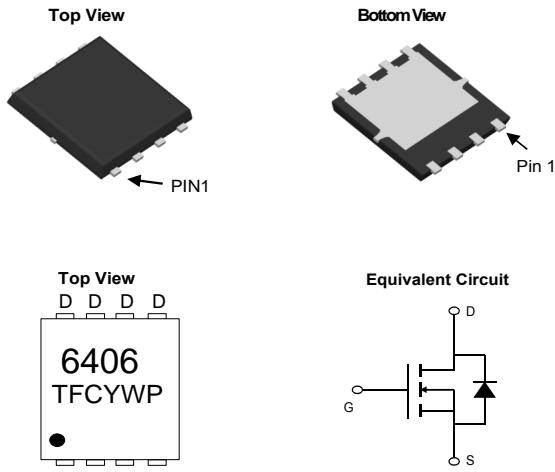


**30V N-Channel MOSFET**

<p><b>General Features</b></p> <p> <math>V_{DS} = 30V</math>  <math>I_D</math> (at <math>V_{GS} = 10V</math>) = 140A  <math>R_{DS(on)}</math> (at <math>V_{GS} = 10V</math>) &lt; 2.5mΩ  <math>R_{DS(on)}</math> (at <math>V_{GS} = 4.5V</math>) &lt; 3.5mΩ          100% UIS Tested          100% <math>R_g</math> Tested       </p> <ul style="list-style-type: none"> <li>Latest Trench Power LV technology</li> <li>Very Low <math>R_{DS(on)}</math> at 4.5V<math>_{GS}</math></li> <li>Low Gate Charge</li> <li>High Current Capability</li> <li>RoHS and Halogen-Free Compliant</li> </ul> <p><b>Application</b></p> <ul style="list-style-type: none"> <li>DC/DC Converters in Computing, Servers, and POL</li> <li>Isolated DC/DC Converters in Telecom and Industrial</li> </ul>	<p><b>PDFN5X6-8L</b></p>  <p>Y :year code W :week code</p>
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**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	140	A
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	280	
Continuous Drain Current	$I_{DSM}$	25	A
$T_A=70^\circ C$		19	
Avalanche Current <sup>C</sup>	$I_{AS}$	60	A
Avalanche energy L=0.1mH <sup>C</sup>	$E_{AS}$	180	mJ
Power Dissipation <sup>B</sup>	$P_D$	110	W
Power Dissipation <sup>A</sup>	$P_{DSM}$	2.3	W
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

**Thermal Characteristics**

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	14	17	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		40	55	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	0.85	1.1	°C/W



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Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30	36		V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 16\text{V}$			10	$\text{uA}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.3	1.8	2.4	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		2.1	2.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		2.6	3.5	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		130		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.67	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				140	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		4300	5200	pF
$C_{\text{oss}}$	Output Capacitance			720		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			420		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1	2	3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		70	100	nC
$Q_g(4.5\text{V})$	Total Gate Charge			33		nC
$Q_{\text{gs}}$	Gate Source Charge			10		nC
$Q_{\text{gd}}$	Gate Drain Charge			15		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		10		ns
$t_r$	Turn-On Rise Time			6.5		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			75		ns
$t_f$	Turn-Off Fall Time			18		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		30		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		15		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $150^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

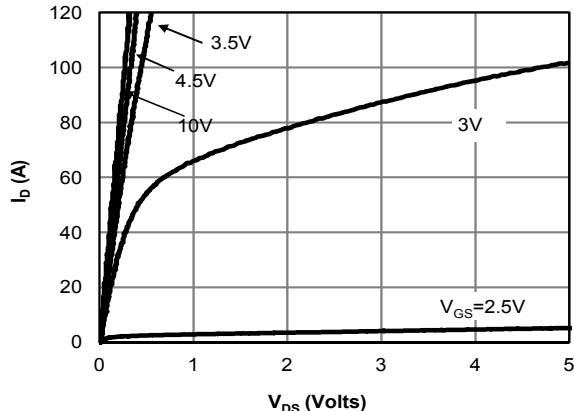


Fig 1: On-Region Characteristics (Note E)

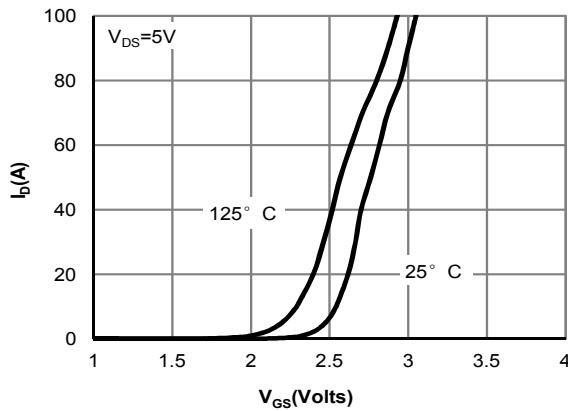


Figure 2: Transfer Characteristics (Note E)

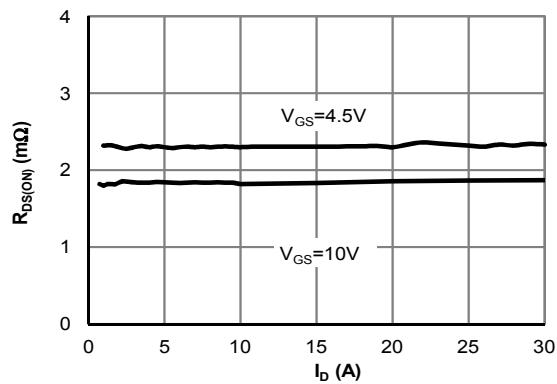


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

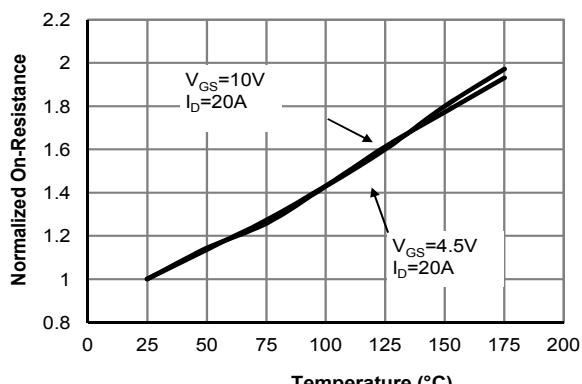


Figure 4: On-Resistance vs. Junction Temperature (Note E)

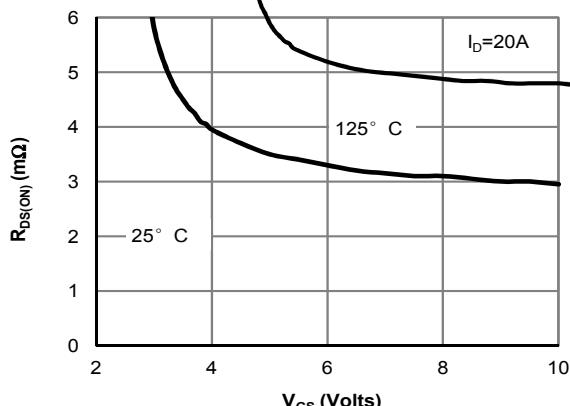


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

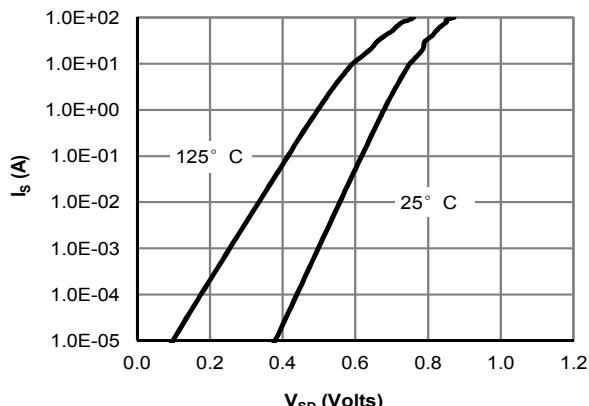


Figure 6: Body-Diode Characteristics (Note E)



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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

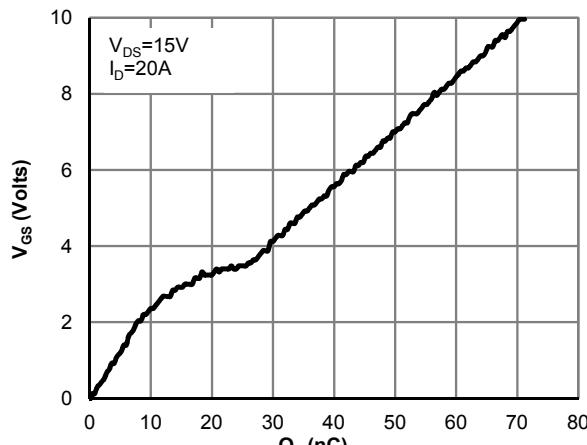


Figure 7: Gate-Charge Characteristics

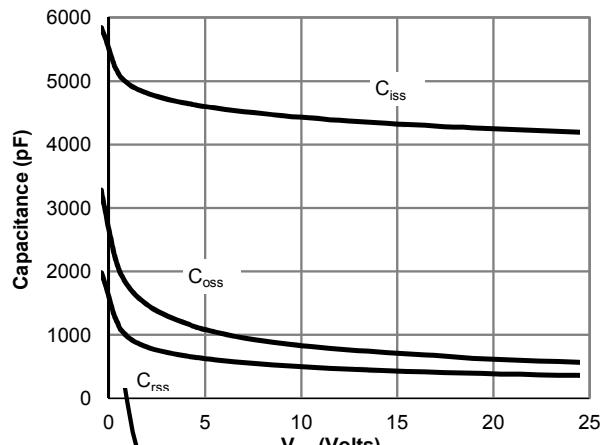


Figure 8: Capacitance Characteristics

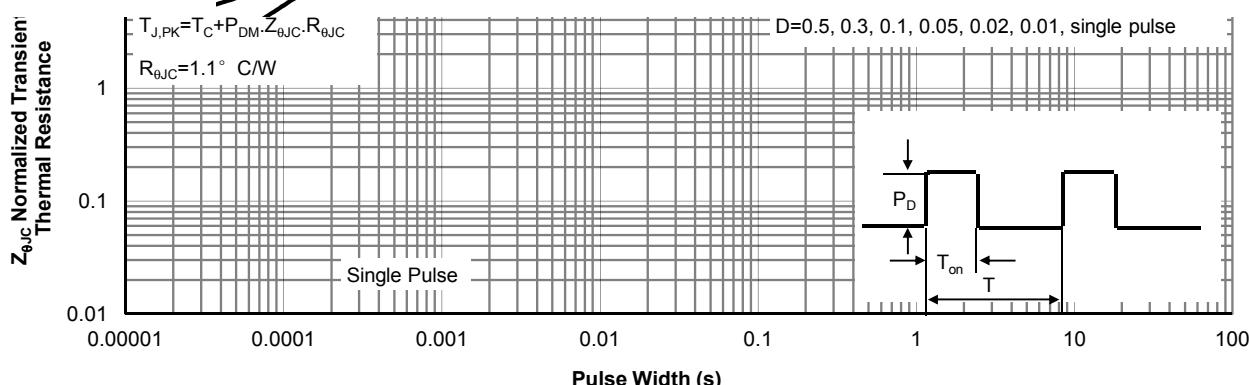
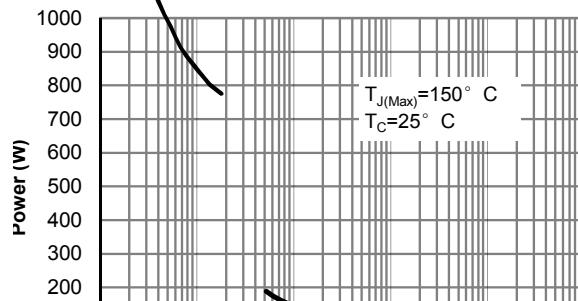
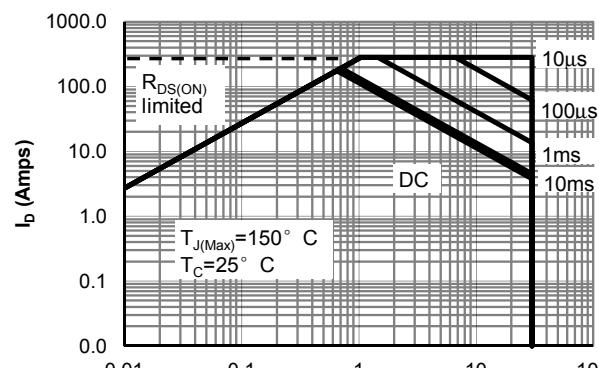


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

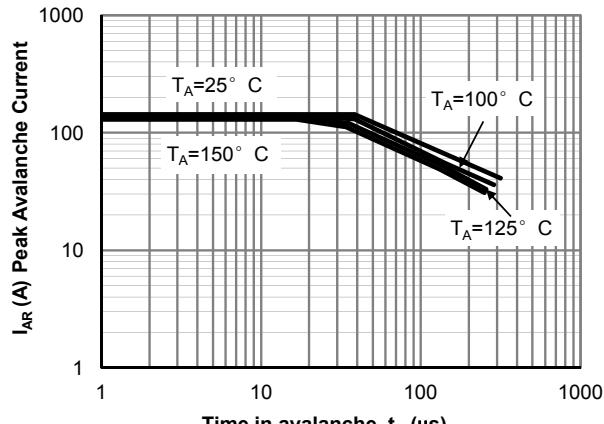


Figure 12: Single Pulse Avalanche capability  
(Note C)

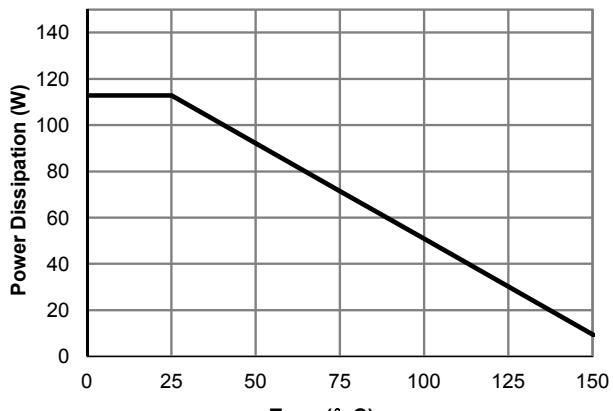


Figure 13: Power De-rating (Note F)

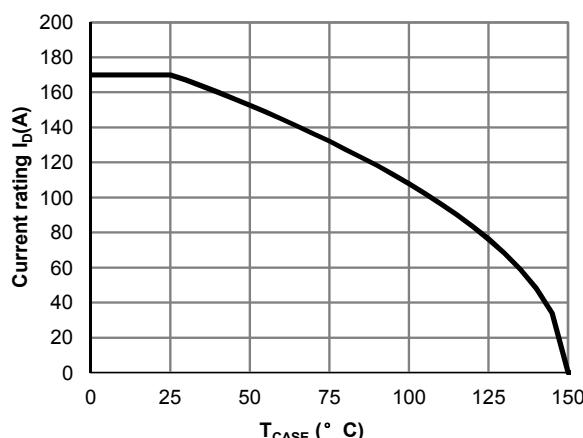


Figure 14: Current De-rating (Note F)

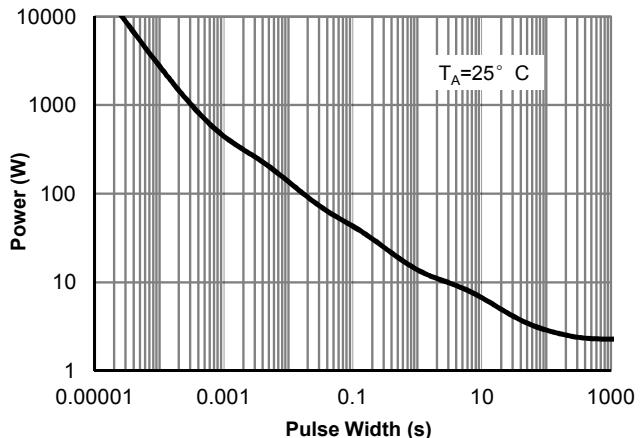


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

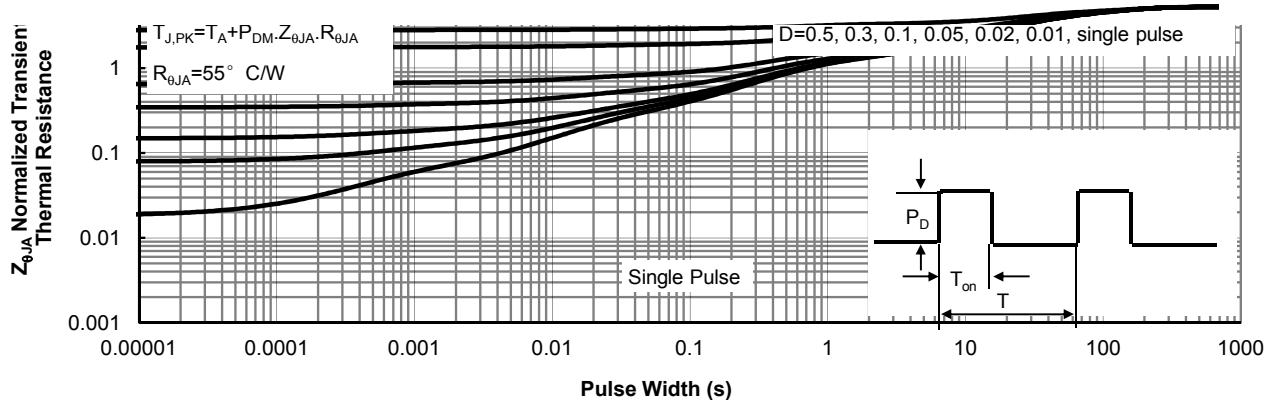
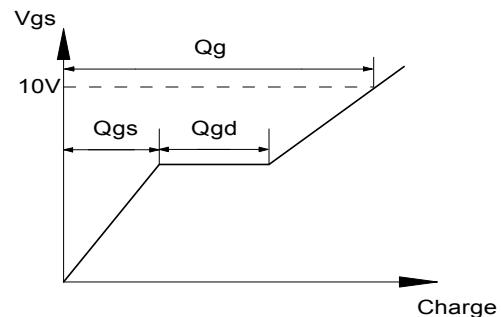
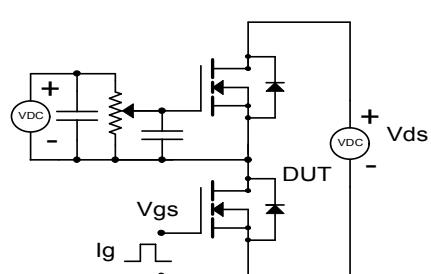
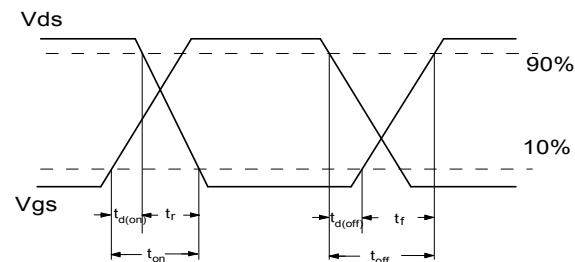
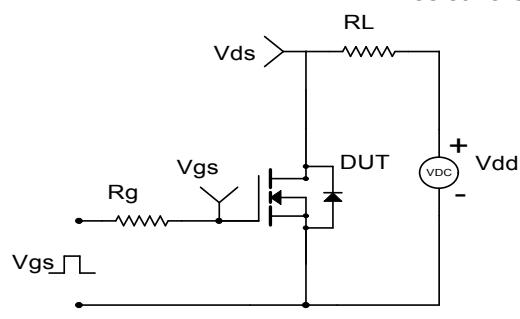


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

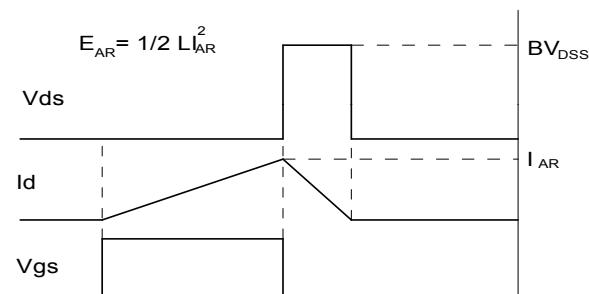
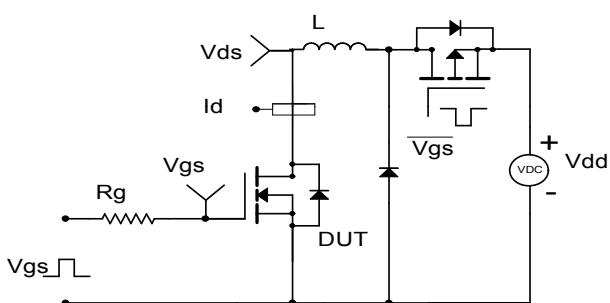
Gate Charge Test Circuit & Waveform



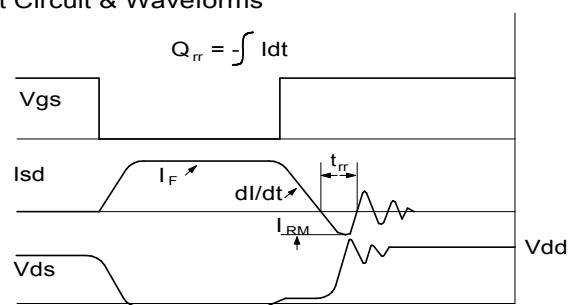
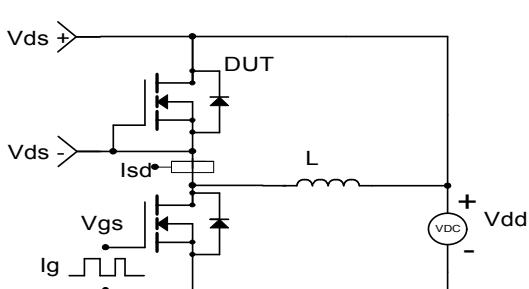
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



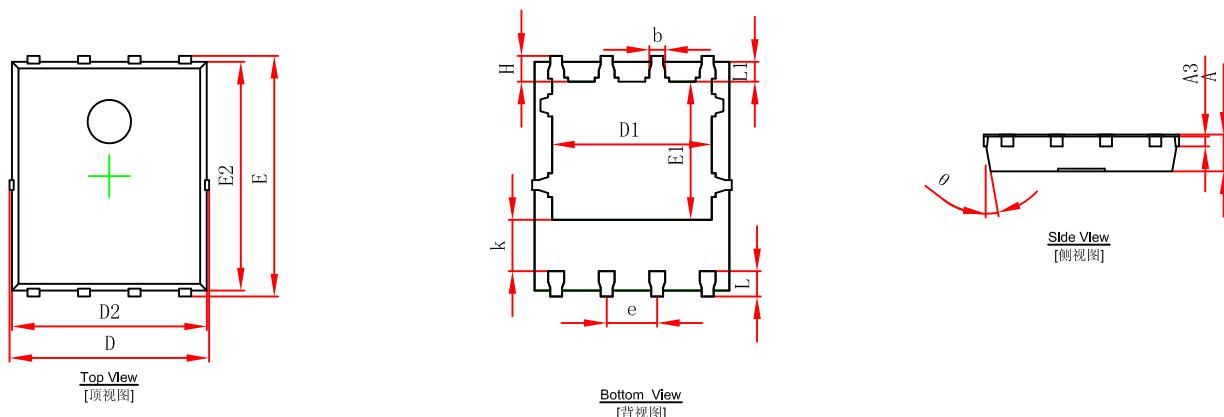


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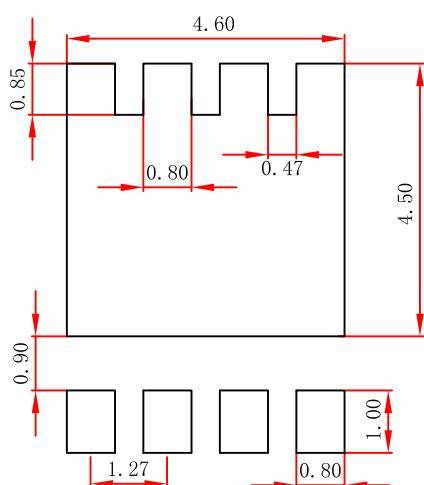
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## PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

## PDFNWB5x6-8L Suggested Pad Layout



Note:  
1. Controlling dimension:in millimeters.  
2.General tolerance: $\pm 0.05$ mm.  
3.The pad layout is for reference purposes only.